

INTERNATIONAL SEARCH REPORT

International Application No

/IB2005/050828

A. CLASSIFICATION OF SUBJECT MATTER

G06T7/00

G06T5/00

G06T5/20

According to International Patent Classification (IPC) or to both national classification and IPC

B. FIELDS SEARCHED

Minimum documentation searched (classification system followed by classification symbols)

G06T

Documentation searched other than minimum documentation to the extent that such documents are included in the fields searched

Electronic data base consulted during the international search (name of data base and, where practical, search terms used)

EPO-Internal, WPI Data, INSPEC

C. DOCUMENTS CONSIDERED TO BE RELEVANT

Category *	Citation of document, with indication, where appropriate, of the relevant passages	Relevant to claim No.
X	<p>H. BOUMA: "Edge Location and Curvature" POSTER TU/E RESEARCH DAY, 'Online! May 2003 (2003-05), XP002366702 Retrieved from the Internet: URL: http://www.bmi2.bmt.tue.nl/image-analysis/people/hbouma/research/ 'retrieved on 2006-02-06! the whole document</p> <p style="text-align: center;">----- -/-</p>	1-3, 9, 10



Further documents are listed in the continuation of box C.



Patent family members are listed in annex.

* Special categories of cited documents:

- *A* document defining the general state of the art which is not considered to be of particular relevance
- *E* earlier document but published on or after the international filing date
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- *O* document referring to an oral disclosure, use, exhibition or other means
- *P* document published prior to the international filing date but later than the priority date claimed

T later document published after the international filing date or priority date and not in conflict with the application but cited to understand the principle or theory underlying the invention

X document of particular relevance; the claimed invention cannot be considered novel or cannot be considered to involve an inventive step when the document is taken alone

Y document of particular relevance; the claimed invention cannot be considered to involve an inventive step when the document is combined with one or more other such documents, such combination being obvious to a person skilled in the art.

G document member of the same patent family

Date of the actual completion of the international search

9 February 2006

Date of mailing of the international search report

21/02/2006

Name and mailing address of the ISA

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C.(Continuation) DOCUMENTS CONSIDERED TO BE RELEVANT		
Category *	Citation of document, with indication, where appropriate, of the relevant passages	Relevant to claim No.
X	<p>VERBEEK P W ET AL: "On the location error of curved edges in low-pass filtered 2-D and 3-D images"</p> <p>IEEE TRANSACTIONS ON PATTERN ANALYSIS AND MACHINE INTELLIGENCE USA, vol. 16, no. 7, July 1994 (1994-07), pages 726-733, XP002366703 ISSN: 0162-8828 section III. "Spherical Step Edge Objects in High-Dimensional Space"</p> <p>-----</p>	1-3,9,10
A	<p>VAN VLIET L J ET AL: "Edge localization by MoG filters: multiple-of-Gaussians"</p> <p>PATTERN RECOGNITION LETTERS NETHERLANDS, vol. 15, no. 5, May 1994 (1994-05), pages 485-496, XP002366704 ISSN: 0167-8655 abstract</p> <p>-----</p>	1-10
A	<p>KAYARGADDE V ET AL: "Estimation of edge parameters and image blur from local derivatives"</p> <p>JOURNAL ON COMMUNICATIONS HUNGARY, vol. 45, July 1994 (1994-07), pages 33-35, XP008059520 ISSN: 0866-5583 section 1. "Introduction" section 4. "Estimation of Edge Parameters"</p> <p>-----</p>	1-10
T	<p>BOUMA H ET AL: "Correction for the dislocation of curved surfaces caused by the PSF in 2D and 3D CT images"</p> <p>IEEE TRANSACTIONS ON PATTERN ANALYSIS AND MACHINE INTELLIGENCE IEEE COMPUT. SOC USA, vol. 27, no. 9, September 2005 (2005-09), pages 1501-1507, XP002366853 ISSN: 0162-8828 the whole document</p> <p>-----</p>	1-10
T	<p>MENDONCA P R S ET AL: "Bias in the localization of curved edges"</p> <p>COMPUTER VISION - ECCV 2004. 8TH EUROPEAN CONFERENCE ON COMPUTER VISION. PROCEEDINGS (LECTURE NOTES IN COMPUT. SCI. VOL.3022) SPRINGER-VERLAG BERLIN, GERMANY, vol. 2, 2004, pages 554-565 Vol.2, XP019005853 ISBN: 3-540-21983-8 abstract figure 3 section 4 "Correction of Bias in Edge Localization" section 5 "Experimental Results"</p> <p>-----</p>	1-10